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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
ITO, Munehiro

New York, New York
Date: January 25, 2006

Serial No.: 10/723,278

Group Art Unit: 2813

Date Filed: November 24, 2003

For: METHOD FOR TESTING SEMICONDUCTOR MEMORY DEVICE AND TEST
CIRCUIT FOR SEMICONDUCTOR MEMORY DEVICE

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

STATUS INQUIRY LETTER

Sir:

We filed the above application with the U. S. Patent and Trademark Office on November 24, 2003.

As of this date, we have not received a first Office Action from the Patent Office. Kindly advise us of the status of this application.

Respectfully Submitted,

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